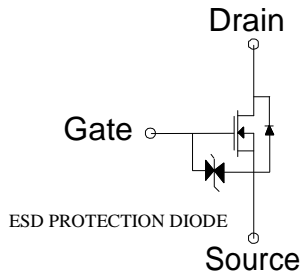
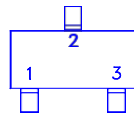


N-Channel High Density Trench MOSFET



SOT-523



1. GATE
2. DRAIN
3. SOURCE

PRODUCT SUMMARY

$V_{(BR)DSS}$	$R_{DS(ON)}$	I_D
60V	2Ω	600mA

ABSOLUTE MAXIMUM RATINGS ($T_A = 25\text{ }^\circ\text{C}$ Unless Otherwise Noted)

PARAMETERS/TEST CONDITIONS	SYMBOL	LIMITS	UNITS
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	±20	V
Continuous Drain Current	I_D	$T_C = 25\text{ }^\circ\text{C}$	600
		$T_C = 100\text{ }^\circ\text{C}$	380
Pulsed Drain Current ¹	I_{DM}	1	A
Power Dissipation	P_D	$T_C = 25\text{ }^\circ\text{C}$	0.35
		$T_C = 100\text{ }^\circ\text{C}$	0.14
Operating Junction & Storage Temperature Range	T_j, T_{stg}	-40 to 150	$^\circ\text{C}$

THERMAL RESISTANCE RATINGS

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Ambient	$R_{\theta JA}$		350	$^\circ\text{C} / \text{W}$

¹Pulse width limited by maximum junction temperature.

ELECTRICAL CHARACTERISTICS ($T_J = 25\text{ }^\circ\text{C}$, Unless Otherwise Noted)

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
STATIC						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	60			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1	1.5	2.5	V
Gate-Body Leakage	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 16\text{V}$			±30	μA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 48\text{V}, V_{GS} = 0\text{V}$			1	μA
		$V_{DS} = 40\text{V}, V_{GS} = 0\text{V}, T_J = 125\text{ }^\circ\text{C}$			30	μA
On-State Drain Current ¹	$I_{D(ON)}$	$V_{DS} = 10\text{V}, V_{GS} = 10\text{V}$	1			A
Drain-Source On-State Resistance ¹	$R_{DS(ON)}$	$V_{GS} = 3.5\text{V}, I_D = 10\text{mA}$		2.1	5	Ω
		$V_{GS} = 4.5\text{V}, I_D = 100\text{mA}$		1.7	3	
		$V_{GS} = 10\text{V}, I_D = 200\text{mA}$		1.6	2	
Forward Transconductance ¹	g_{fs}	$V_{DS} = 20\text{V}, I_D = 200\text{mA}$		3		S

DYNAMIC						
Input Capacitance	C_{iss}	$V_{GS} = 0V, V_{DS} = 25V, f = 1MHz$		42		pF
Output Capacitance	C_{oss}			7		
Reverse Transfer Capacitance	C_{rss}			3		
Total Gate Charge ²	Q_g	$V_{DS} = 30V_{(BR)DSS}, V_{GS} = 10V,$ $I_D = 200mA$		1.8		nC
Gate-Source Charge ²	Q_{gs}			0.9		
Gate-Drain Charge ²	Q_{gd}			0.2		
SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS($T_J = 25^\circ C$)						
Continuous Current	I_S	$I_F = 200mA, V_{GS} = 0V$			300	mA
Forward Voltage ¹	V_{SD}				1.2	V

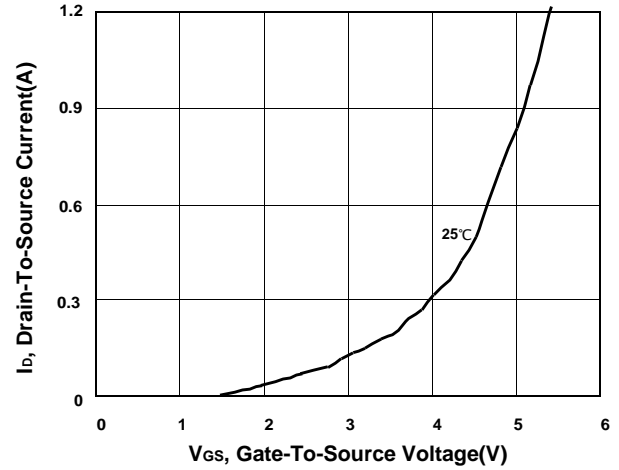
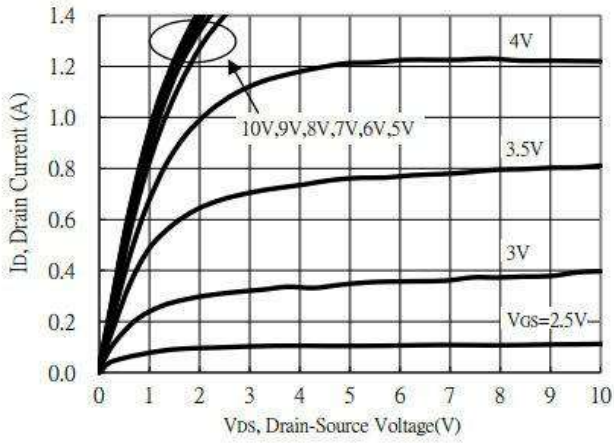
¹Pulse test : Pulse W idth $\leq 300 \mu sec$, Duty Cycle $\leq 2\%$.

²Independent of operating temperature.

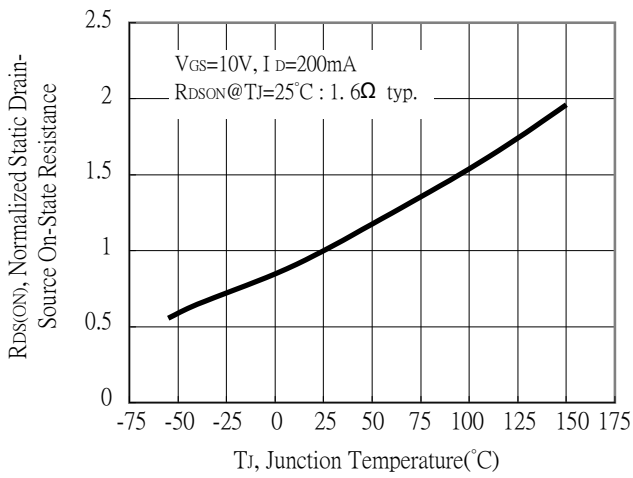
³Pulse width limited by maximum junction temperature.

REMARK: ESD Protected Gate, 2KV HBM

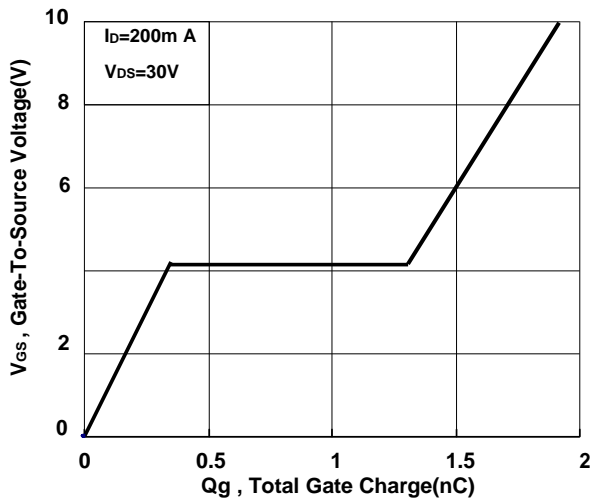
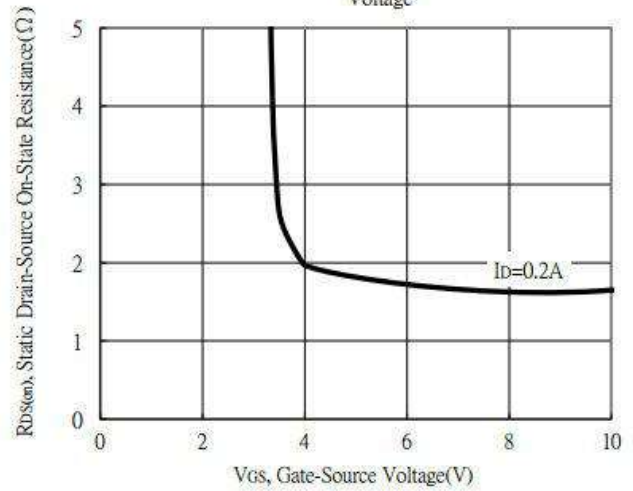
Typical Output Characteristics



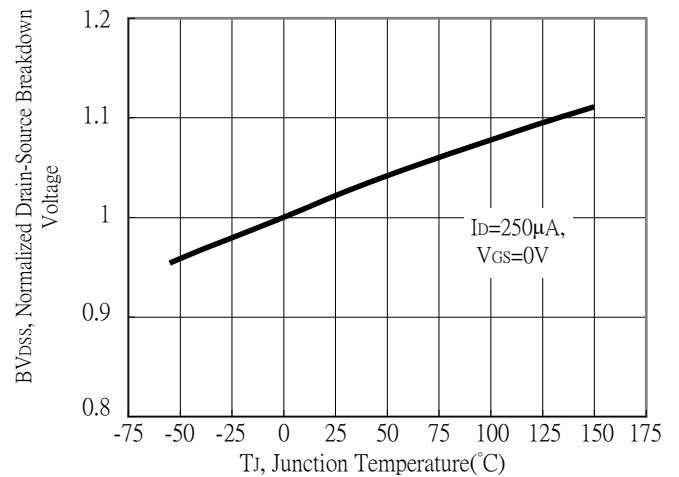
Drain-Source On-State Resistance vs Junction Temperature



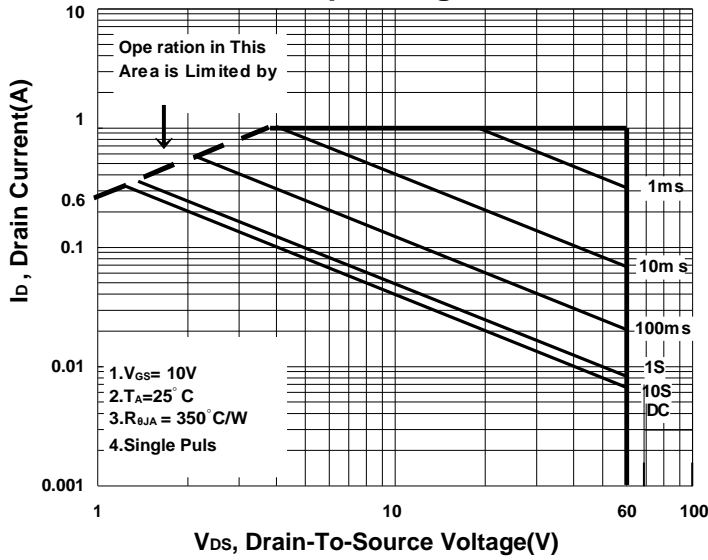
Static Drain-Source On-State Resistance vs Gate-Source Voltage



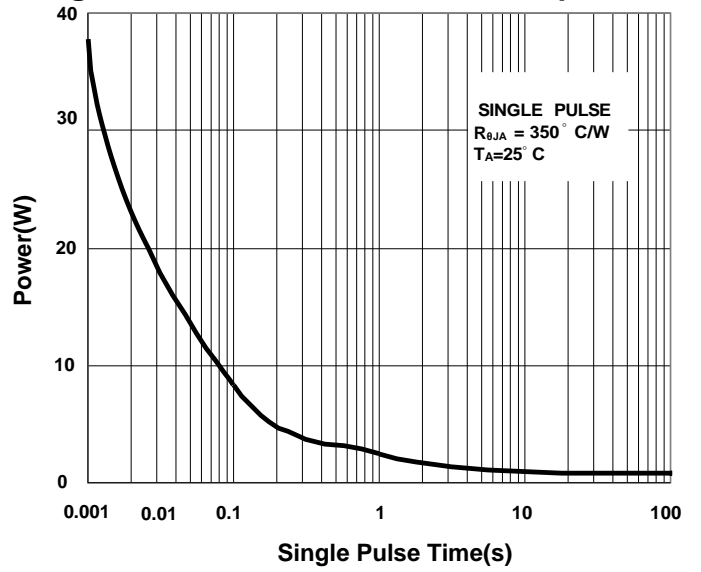
Brekdown Voltage vs Ambient Temperature



Safe Operating Area



Single Pulse Maximum Power Dissipation



Transient Thermal Response Curves

